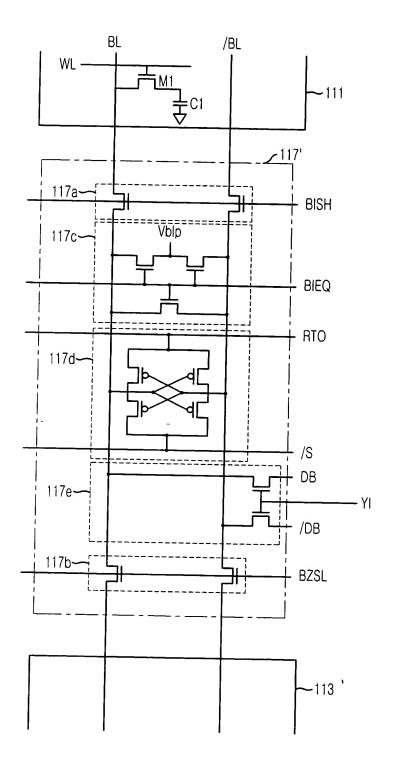
Attny Docket No. 29926/39501 Title: "Memory Device in Semiconductor For Enhancing Ability of Test" Inventor: Byung-Jae Lee FIG 1 Sheet 1 of 13 FIG. 1 (PRIOR ART) 2000 OUTPUT BUFFER 3 I/O SENSE AMPLIFIER I/O SENSE AMPLIFIER CELL ARRAY CELL ARRAY BITLINE SENSE AMPLIFIER CELL ARRAY OELL ARRAY BITLINE SENSE AMPLIFIER BITLINE SENSE AMPLIFIER CELL CELL ARRAY CELL BLOCK

Inventor: Byung-Jae Lee

FIG 2

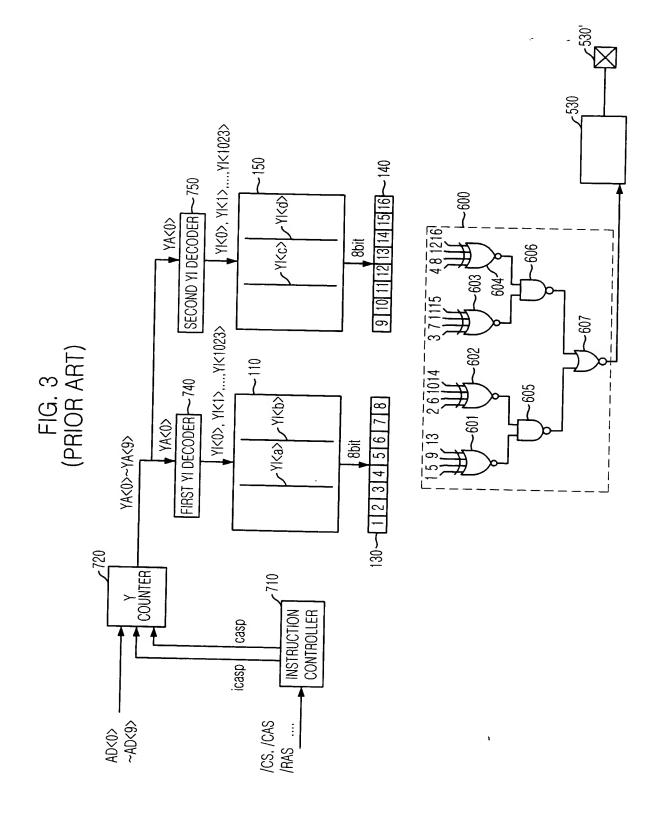
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FIG. 2 (PRIOR ART)



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FIG 3

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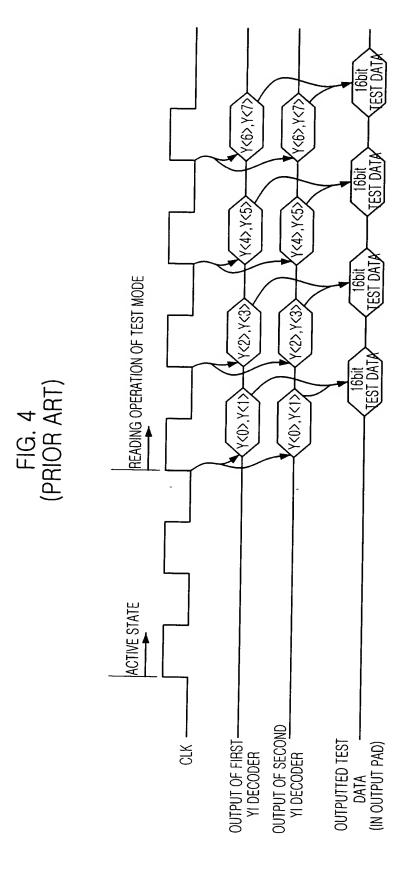
Attny Docket No. 29926/39501

Title: "Memory Device in Semiconductor For Enhancing Ability

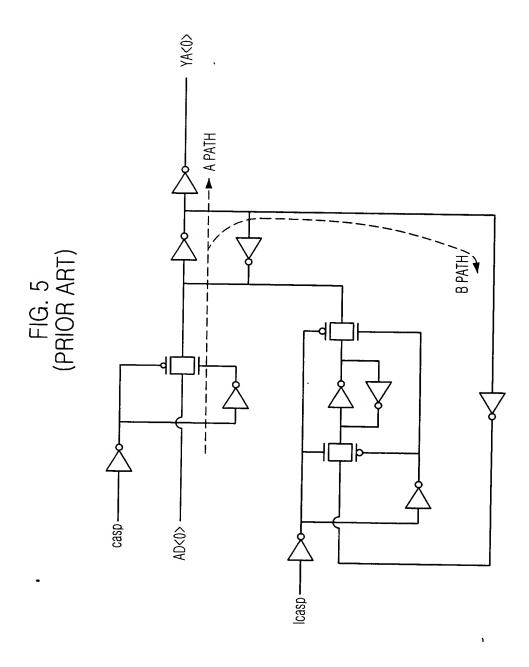
of Test"

Inventor: Byung-Jae Lee FIG 4

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of Test"
Inventor: Byung-Jae Lee
FIG 5
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Inventor: Byung-Jae Lee
FIG 6 Sheet 6 of 13 ~150 YK1>, YK3>,..., YK1023> 530 -009~ YA<0>H enable SECOND YI DECODER -750 FIG. 6 (PRIOR ART) /YKg>/ 16bit 611 YIĆe> | YIĆf> | ~614 909 YK0>, YK2>,..., YK1022>,110' 620 8 1216 YA<0>L enable FIRST YI DECODER -740 YIĆb> | YIĆC> | YIĆd> 604 16bit YA<0>~YA<9> -607 //ka> casp INSTRUCTION CONTROLLER

icasp

/CS. /CAS

AD<0> ~AD<9>

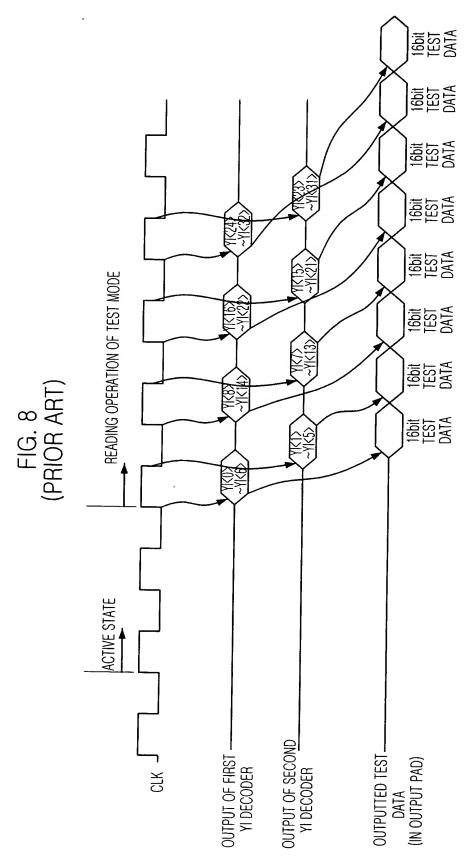
Title: "Memory Device in Semiconductor For Enhancing Ability of Test"
Inventor: Byung-Jae Lee
FIG 7
Sheet 7 of 13 READING OPERATION OF TEST MODE FIG. 7 (PRIOR ART) OUTPUT OF SECOND
YI DECODER OUTPUTTED TEST
DATA
(IN OUTPUT PAD) Output of First-Yi Decoder

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Inventor: Byung-Jae Lee

FIG 8

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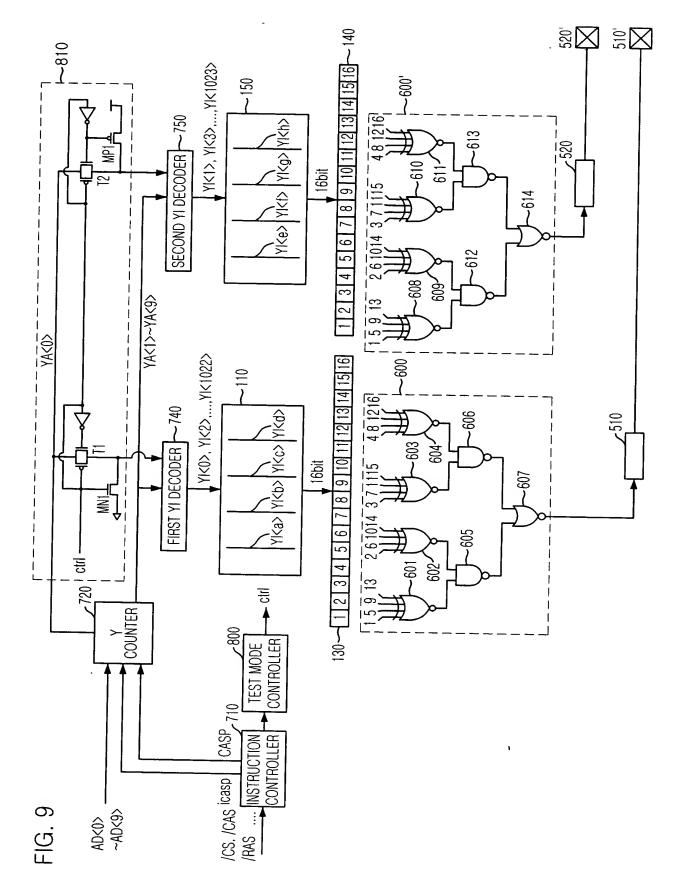
Attny Docket No. 29926/39501

Title: "Memory Device in Semiconductor For Enhancing Ability

of Test"

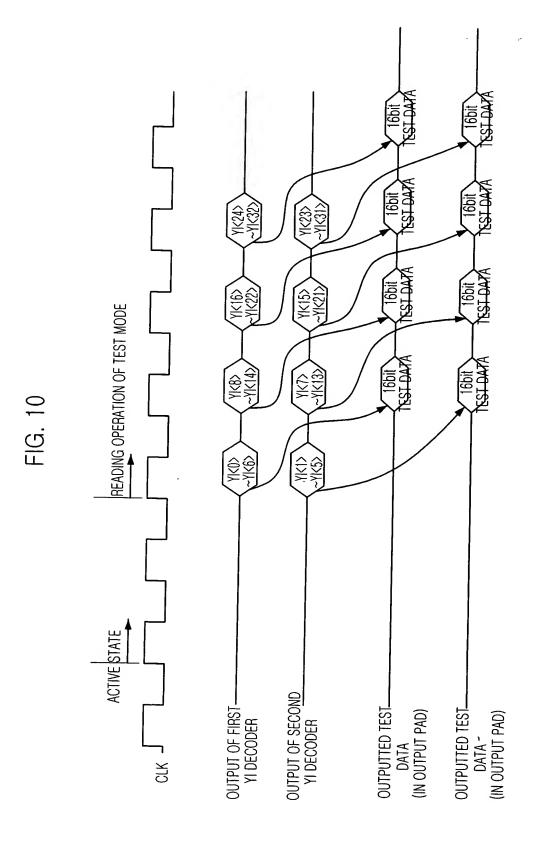
Inventor: Byung-Jae Lee

FIG 9 Sheet 9 of 13



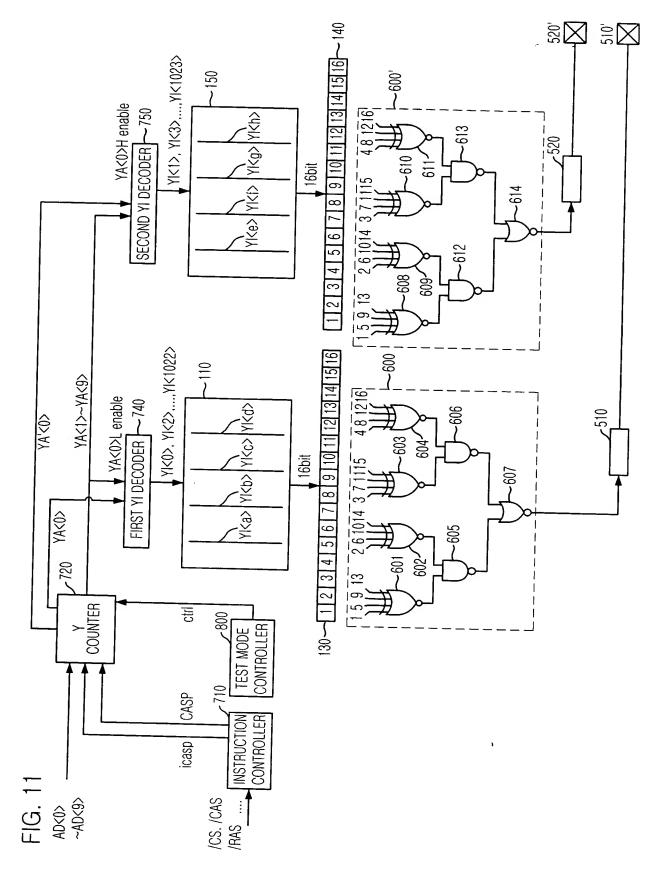
Inventor: Byung-Jae Lee FIG 10

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Inventor: Byung-Jae Lee

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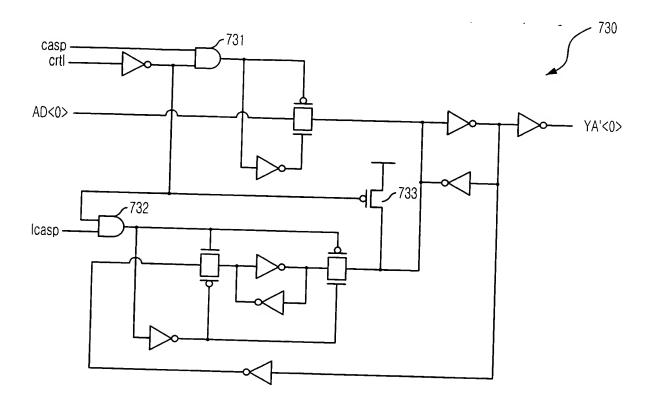


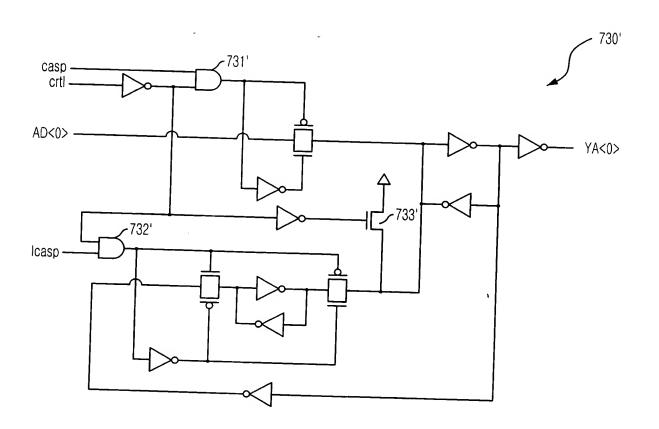
Title: "Memory Device in Semiconductor For Enhancing Ability

of Test"

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FIG. 12





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Inventor: Byung-Jae Lee

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FIG. 13

